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Application/Control No.	Applicant(s)/Patent under Reexamination
10/760,178	SAKAI, HIROFUMI
Examiner	Art Unit
Wai-Sing Louie	2814

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Class	Subclass	Date	Examiner
257	40, 79-84	5/3/2005	WSL
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INT	ERFERENC	E SEARCI	HED
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	DATE	EXMR
OLED, deterioration, hole transport ayer, intensity, electron transport layer	5/3/2005	WSL
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